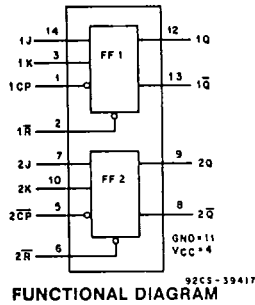


CD54/74HC73
CD54/74HCT73

File Number 1721

HARRIS SEMICOND SECTOR 27E D ■ 4302271 0017511 5 ■ HAS



Dual J-K Flip-Flop with Reset
Negative-Edge Trigger

Type Features:

- Hysteresis on clock inputs for improved noise immunity and increased input Rise and Fall times.
- Asynchronous Reset
- Complementary Outputs
- Buffered Inputs
- Typical $f_{max} = 60\text{MHz}$ @ $V_{cc} = 5\text{V}$, $C_L = 15\text{pF}$, $T_A = 25^\circ\text{C}$

Family Features:

- Fanout (Over Temperature Range):
Standard Outputs - 10 LSTTL Loads
Bus Driver Outputs - 15 LSTTL Loads
- Wide Operating Temperature Range:
CD74HC/HCT: -40 to $+85^\circ\text{C}$
- Balanced Propagation Delay and Transition Times
- Significant Power Reduction Compared to LSTTL Logic ICs
- Alternate Source is Philips/Signetics
- CD54HC/CD74HC Types:
2 to 6 V Operation
High Noise Immunity: $N_{IL} = 30\%$, $N_{IH} = 30\%$ of V_{cc} , @ $V_{cc} = 5\text{V}$
- CD54HCT/CD74HCT Types:
4.5 to 5.5 V Operation
Direct LSTTL Input Logic Compatibility
 $V_{IL} = 0.8\text{V Max.}$, $V_{IH} = 2\text{V Min.}$
CMOS Input Compatibility $I_i \leq 1\mu\text{A}$ @ V_{OL} , V_{OH}

The RCA-CD54/74HC73 and CD54/74HCT73 utilize silicon-gate CMOS technology to achieve operating speeds equivalent to LSTTL parts. They exhibit the low power consumption of standard CMOS integrated circuits, together with the ability to drive 10 LSTTL loads.

These flip-flops have independent J, K, Reset and Clock inputs and Q and \bar{Q} outputs. They change state on the negative-going transition of the clock pulse. Reset is accomplished asynchronously by a low-level input. This device is functionally identical to the HC/HCT 107 but differs in terminal assignment and in some parametric limits.

The 54HCT/74HCT logic family is functionally as well as pin-compatible with the standard 54LS/74LS logic family.

The CD54HC73 and CD54HCT73 are supplied in 14-lead hermetic dual-in-line ceramic packages (F suffix). The CD74HC73 and CD74HCT73 are supplied in 14-lead dual-in-line plastic packages (E suffix) and in 14-lead dual-in-line surface-mount plastic packages (M suffix). Both types are also available in chip form (H suffix).

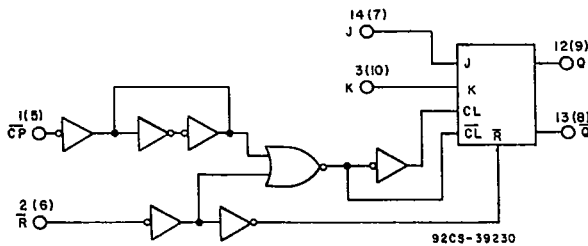


Fig. 1 - Logic diagram.

TRUTH TABLE
(EACH FLIP-FLOP)

INPUTS				OUTPUTS	
\bar{R}	\bar{CP}	J	K	Q	\bar{Q}
L	X	X	X	L	H
H	~	L	L	No change	
H	~	H	L	H	L
H	~	L	H	L	H
H	~	H	H	Toggle	
H	H	X	X	No change	

H = High Level (Steady State)
L = Low Level (Steady State)
X = Irrelevant
~ = High-to-Low transition

CD54/74HC73
CD54/74HCT73

MAXIMUM RATINGS, Absolute-Maximum Values:

DC SUPPLY-VOLTAGE, (V_{CC}):
(Voltages referenced to ground) -0.5 to +7 V

DC INPUT DIODE CURRENT, I_{IK} (FOR $V_i < -0.5$ V OR $V_i > V_{CC} + 0.5$ V) ± 20 mA

DC OUTPUT DIODE CURRENT, I_{OK} (FOR $V_o < -0.5$ V OR $V_o > V_{CC} + 0.5$ V) ± 20 mA

DC DRAIN CURRENT, PER OUTPUT (I_o) (FOR -0.5 V $< V_o < V_{CC} + 0.5$ V) ± 25 mA

DC V_{CC} OR GROUND CURRENT (I_{CC}) ± 50 mA

POWER DISSIPATION PER PACKAGE (P_o):

For $T_A = -40$ to $+60^\circ\text{C}$ (PACKAGE TYPE E) 500 mW

For $T_A = +60$ to $+85^\circ\text{C}$ (PACKAGE TYPE E) Derate Linearly at 8 mW/ $^\circ\text{C}$ to 300 mW

For $T_A = -55$ to $+100^\circ\text{C}$ (PACKAGE TYPE F, H) 500 mW

For $T_A = +100$ to $+125^\circ\text{C}$ (PACKAGE TYPE F, H) Derate Linearly at 8 mW/ $^\circ\text{C}$ to 300 mW

For $T_A = -40$ to $+70^\circ\text{C}$ (PACKAGE TYPE M) 400 mW

For $T_A = +70$ to $+125^\circ\text{C}$ (PACKAGE TYPE M) Derate Linearly at 6 mW/ $^\circ\text{C}$ to 70 mW

OPERATING-TEMPERATURE RANGE (T_A):

PACKAGE TYPE F, H -55 to $+125^\circ\text{C}$

PACKAGE TYPE E, M -40 to $+85^\circ\text{C}$

STORAGE TEMPERATURE (T_{stg}) -65 to $+150^\circ\text{C}$

LEAD TEMPERATURE (DURING SOLDERING):

At distance $1/16 \pm 1/32$ in. (1.59 ± 0.79 mm) from case for 10 s max $+265^\circ\text{C}$

Unit inserted into a PC Board (min. thickness $1/16$ in., 1.59 mm) with solder contacting lead tips only $+300^\circ\text{C}$

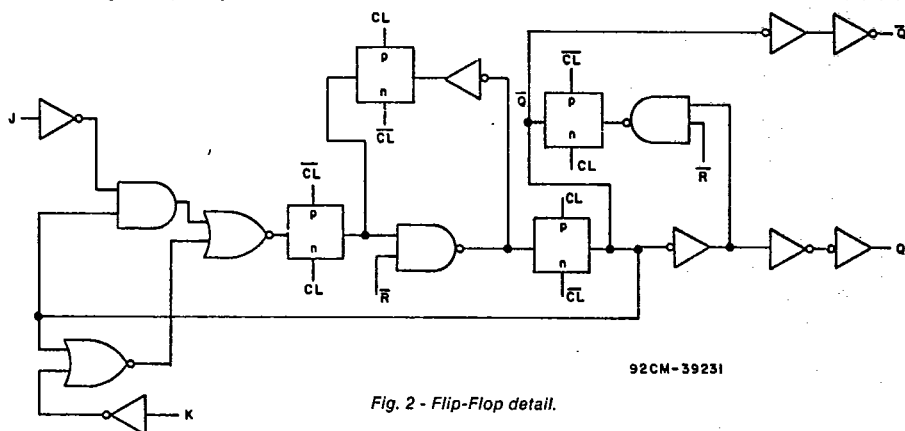


Fig. 2 - Flip-Flop detail.

RECOMMENDED OPERATING CONDITIONS:

For maximum reliability, nominal operating conditions should be selected so that operation is always within the following ranges:

CHARACTERISTIC	LIMITS		UNITS
	MIN.	MAX.	
Supply-Voltage Range (For $T_A =$ Full Package-Temperature Range) V_{CC} †	2	6	V
CD54/74HC Types	4.5	5.5	
CD54/74HCT Types			
DC Input or Output Voltage V_i, V_o	0	V_{CC}	-V
Operating Temperature T_A :			
CD74 Types	-40	+85	$^\circ\text{C}$
CD54 Types	-55	+125	
Input Rise and Fall Times t_r, t_f			
at 2 V	0	1000	ns
at 4.5 V	0	500	
at 6 V	0	400	

*Unless otherwise specified, all voltages are referenced to Ground.

†Applicable for all inputs except clock.

HARRIS SEMICOND SECTOR 27E D 4302271 0017512 7 HAS

CD54/74HC73
CD54/74HCT73

STATIC ELECTRICAL CHARACTERISTICS

CHARACTERISTIC	CD74HC73, CD54HC73										CD74HCT73, CD54HCT73										UNITS	
	TEST CONDITIONS			74HC/54HC TYPES			74HC TYPES		54HC TYPES			TEST CONDITIONS		74HCT/54HCT TYPES			74HCT TYPES		54HCT TYPES			
	V _i V	I _o mA	V _{cc} V	+25°C			-40/ +85°C		-55/ +125°C			V _i V	V _{cc} V	+25°C			-40/ +85°C		-55/ +125°C			
				Min	Typ	Max	Min	Max	Min	Max	Min			Max	Min	Typ	Max	Min	Max	Min		Max
High-Level Input Voltage V _{IH}			2	1.5	—	—	1.5	—	1.5	—	—	4.5										V
			4.5	3.15	—	—	3.15	—	3.15	—	—	to	2	—	—	2	—	2	—	—	—	
			6	4.2	—	—	4.2	—	4.2	—	—	5.5										
Low-Level Input Voltage V _{IL}			2	—	—	0.5	—	0.5	—	0.5	—	4.5										V
			4.5	—	—	1.35	—	1.35	—	1.35	—	to	—	—	0.8	—	0.8	—	0.8	—	0.8	
			6	—	—	1.8	—	1.8	—	1.8	—	5.5										
High-Level Output Voltage V _{OH}	V _{IL}	-0.02	2	1.9	—	—	1.9	—	1.9	—	V _{IL}											V
or			4.5	4.4	—	—	4.4	—	4.4	—	or	4.5	4.4	—	—	4.4	—	4.4	—	4.4	—	
CMOS Loads	V _{IH}		6	5.9	—	—	5.9	—	5.9	—	V _{IH}											
TTL Loads	V _{IL}										V _{IL}											V
or		-4	4.5	3.98	—	—	3.84	—	3.7	—	or	4.5	3.98	—	—	3.84	—	3.7	—	3.7	—	
	V _{IH}	-5.2	6	5.48	—	—	5.34	—	5.2	—	V _{IH}											
Low-Level Output Voltage V _{OL}	V _{IL}	0.02	2	—	—	0.1	—	0.1	—	0.1	V _{IL}											V
or			4.5	—	—	0.1	—	0.1	—	0.1	—	or	4.5	—	—	0.1	—	0.1	—	0.1	—	
CMOS Loads	V _{IH}		6	—	—	0.1	—	0.1	—	0.1	—	V _{IH}										
TTL Loads	V _{IL}										V _{IL}											V
or		4	4.5	—	—	0.26	—	0.33	—	0.4	or	4.5	—	—	0.26	—	0.33	—	0.4	—	0.4	
	V _{IH}	5.2	6	—	—	0.26	—	0.33	—	0.4	V _{IH}											
Input Leakage Current I _i	V _{cc}		6	—	—	±0.1	—	±1	—	±1	Any Voltage Between V _{cc} & Gnd	5.5	—	—	±0.1	—	±1	—	±1	—	±1	μA
or	Gnd																					
Quiescent Device Current I _{cc}	V _{cc}	0	6	—	—	4	—	40	—	80	V _{cc}	5.5	—	—	4	—	40	—	80	—	80	μA
or	Gnd										or											
Additional Quiescent Device Current per input pin: 1 unit load ΔI _{cc} *											V _{cc} -2.1	4.5 to 5.5	—	100	360	—	450	—	490	—	490	μA

* For dual-supply systems theoretical worst case (V_i = 2.4 V, V_{cc} = 5.5 V) specification is 1.8 mA.

HCT Input Loading Table

Input	Unit Loads*
All	0.3

*Unit Load is ΔI_{cc} limit specified in Static Characteristic Chart, e.g., 360 μA max. @ 25°C.

HARRIS SEMICONDUCTOR 27E D 430227J 0017513 9 HAS

CD54/74HC73
CD54/74HCT73

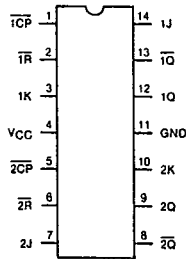
SWITCHING CHARACTERISTICS ($V_{CC}=5\text{ V}$, $T_A=25^\circ\text{C}$, Input $t_r=6\text{ ns}$)

CHARACTERISTIC	SYMBOL	C_L (pF)	TYPICAL		UNITS
			HC	HCT	
Propagation Delay \overline{CP} to Q	t_{PLH}	15	13	16	ns
	t_{PHL}		13	15	ns
	\overline{R} to Q, \overline{Q}		12	14	ns
\overline{CP} Frequency	f_{max}	15	60	60	MHz
Power Dissipation Capacitance*	C_{PD}	—	28	28	pF

* C_{PD} is used to determine the dynamic power consumption, per flip-flop.
 $P_o = C_{PD} V_{CC}^2 f_i + \sum C_L V_{CC}^2 f_o$ where f_i = input frequency, f_o = output frequency,
 C_L = output load capacitance, V_{CC} = supply voltage.

PRE-REQUISITE FOR SWITCHING FUNCTION

CHARACTERISTIC	TEST CONDITION V_{CC} V	LIMITS												UNITS	
		25°C				-40°C to +85°C				-55°C to +125°C					
		HC		HCT		74HC		74HCT		54HC		54HCT			
		Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.		
Pulse Width \overline{CP}	t_w	2	80	—	—	—	100	—	—	—	120	—	—	—	ns
		4.5	16	—	16	—	20	—	20	—	24	—	24	—	
		6	14	—	—	—	17	—	—	—	20	—	—	—	
\overline{R}		2	80	—	—	—	100	—	—	—	120	—	—	—	ns
		4.5	16	—	18	—	20	—	23	—	24	—	27	—	
		6	14	—	—	—	17	—	—	—	20	—	—	—	
Set-up Time J, K to \overline{CP}	t_{su}	2	80	—	—	—	100	—	—	—	120	—	—	—	ns
		4.5	16	—	16	—	20	—	20	—	24	—	24	—	
		6	14	—	—	—	17	—	—	—	20	—	—	—	
Hold Time J, K to \overline{CP}	t_h	2	3	—	—	—	3	—	—	—	3	—	—	—	ns
		4.5	3	—	3	—	3	—	3	—	3	—	3	—	
		6	3	—	—	—	3	—	—	—	3	—	—	—	
Removal Time	t_{rem}	2	80	—	—	—	100	—	—	—	120	—	—	—	ns
		4.5	16	—	12	—	20	—	15	—	24	—	18	—	
		6	14	—	—	—	17	—	—	—	20	—	—	—	
\overline{CP} Frequency	f_{max}	2	6	—	—	—	5	—	—	—	4	—	—	—	MHz
		4.5	30	—	30	—	25	—	25	—	20	—	20	—	
		6	35	—	—	—	29	—	—	—	23	—	—	—	



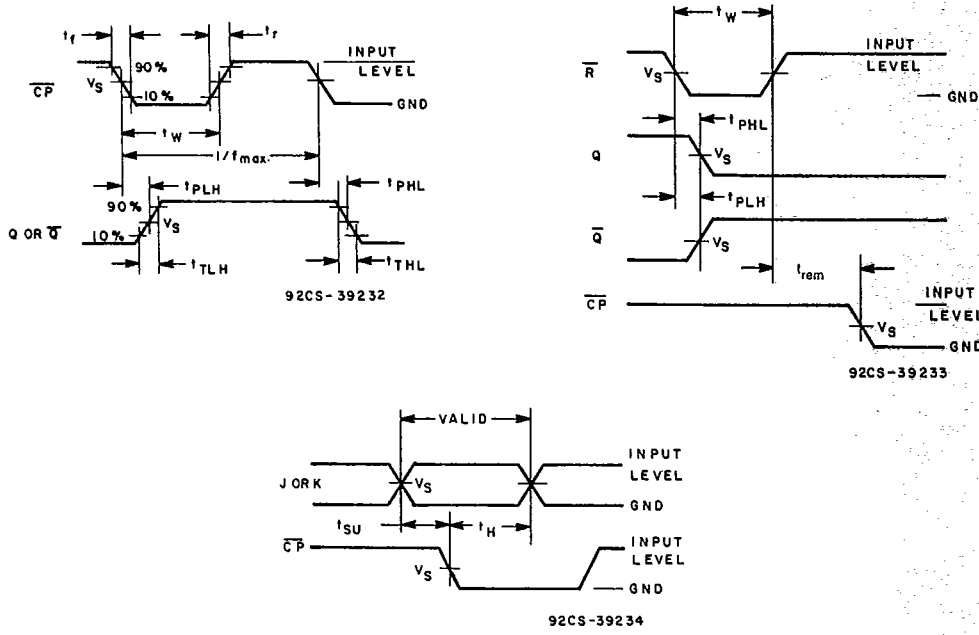
TERMINAL ASSIGNMENT

HARRIS SEMICONDUCTOR 27E D 430227J 00175J4 0 HAS

CD54/74HC73
CD54/74HCT73

SWITCHING CHARACTERISTICS ($C_L = 50$ pF, Input $t_r, t_f = 6$ ns)

CHARACTERISTIC	TEST CONDITION V_{CC} V	LIMITS										UNITS		
		25°C				-40°C to +85°C				-55°C to +125°C				
		HC		HCT		74HC		74HCT		54HC			54HCT	
Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.	Min.	Max.			
Propagation Delay t_{PLH}, t_{PHL} \overline{CP} to Q	2	—	160	—	—	—	200	—	—	—	240	—	—	ns
	4.5	—	32	—	38	—	40	—	48	—	48	—	57	
	6	—	28	—	—	—	34	—	—	—	41	—	—	
\overline{CP} to \overline{Q}	2	—	160	—	—	—	200	—	—	—	240	—	—	ns
	4.5	—	32	—	36	—	40	—	45	—	48	—	54	
	6	—	28	—	—	—	34	—	—	—	41	—	—	
\overline{R} to Q, \overline{Q}	2	—	145	—	—	—	180	—	—	—	220	—	—	ns
	4.5	—	29	—	34	—	36	—	43	—	44	—	51	
	6	—	25	—	—	—	31	—	—	—	38	—	—	
Output Transition Time t_{TLH}, t_{THL}	2	—	75	—	—	—	95	—	—	—	110	—	—	ns
	4.5	—	15	—	15	—	19	—	19	—	22	—	22	
	6	—	13	—	—	—	16	—	—	—	19	—	—	
Input Capacitance C_i		—	10	—	10	—	10	—	10	—	10	—	10	pF



	54/74HC	54/74HCT
Input Level	V_{CC}	3V
Switching Voltage, V_s	50% V_{CC}	1.3 V

Fig. 3 - Transition times, propagation delay times, and setup and hold times.

HARRIS SEMICONDUCTOR 27E D 4302271 0017515 2 HAS